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Substitute for form 1449/PTO  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  <i>(Use as many sheets as necessary)</i>		<b>Complete if Known</b>			
		Application Number	09/841,465-Conf. #5373		
		Filing Date	April 24, 2001		
		First Named Inventor	Seth Haberman		
		Art Unit	2623		
		Examiner Name	C. L. Parry		
Sheet	1	of	2	Attorney Docket Number	2000522.00125US2

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Examiner Signature	/Michael Van Handel/	Date Considered	09/04/2007
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